



## JN-1 SEM Demonstration Standard

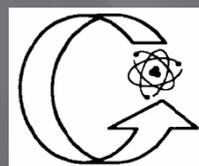
The JN-1 Scanning Electron Microscope demonstration standard is comprised of two 1/2" pin stubs and a 1" mounting base.



One stub has six **conductive** samples consisting of an integrated circuit chip, metal spheres, a set screw, ductile metal fracture, diatoms and a TEM grid. The entire stub surface is coated with about 20nm of Au:Pd.

The second stub has **non-conductive** samples consisting of an integrated circuit chip, paper, glass spheres, fabric and diatoms. The stub is not coated for conductivity and is useful to demonstrate low-vacuum SEM imaging.

Also included is a 1" adapter on which to place one of the 1/2" stubs. The pin on the stub is captured by a spring loaded set screw so the stub is securely held without the use of tools. On the bottom of the 1" adapter there is a 4 mm internal thread which can be used by some SEMs to secure the sample on the stage. The 1" adapter does not have to be used. Curved tip tweezers should be used to handle the stubs. They are commonly available at the SEM supply houses.

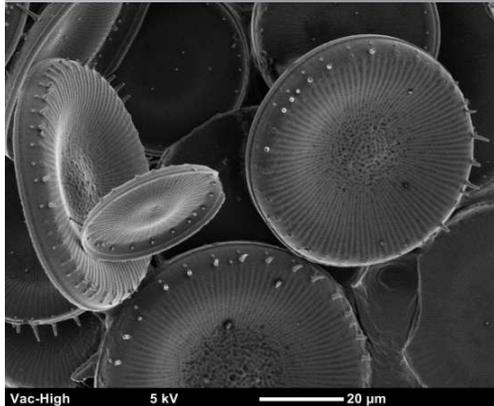


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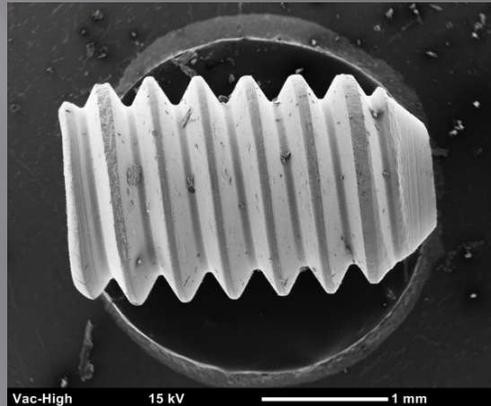
426e BOSTON ST., TOPSFIELD, MA 01983-1216  
TEL 978 887-7000 FAX 978-887-6671

Sales@GellerMicro.com [www.GellerMicro.com](http://www.GellerMicro.com)

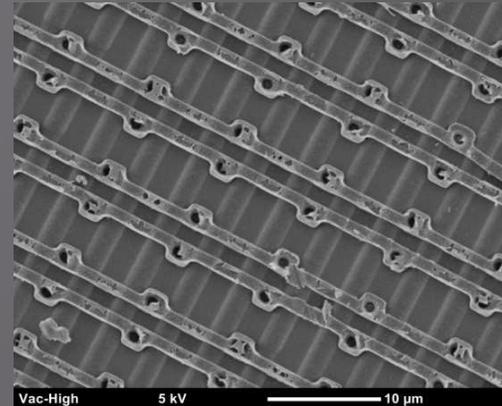
# JN-1 Conductive Sample Images



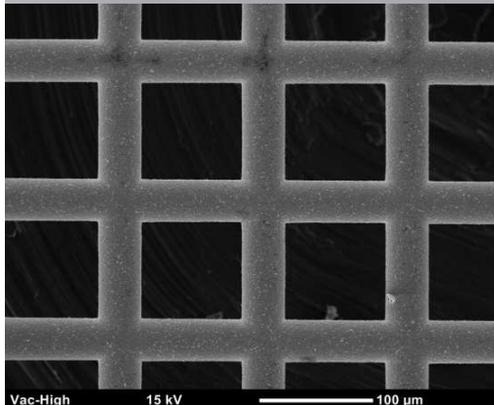
Diatoms



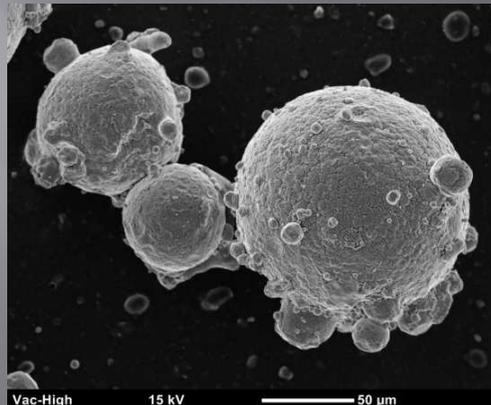
Set screw



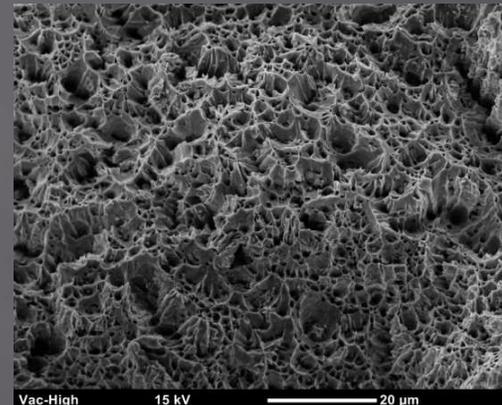
Integrated circuit



TEM grid

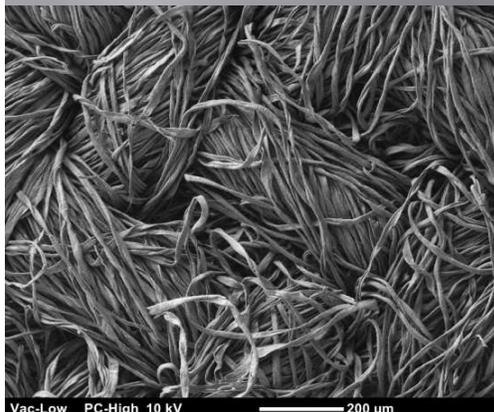


M60 metal spheres

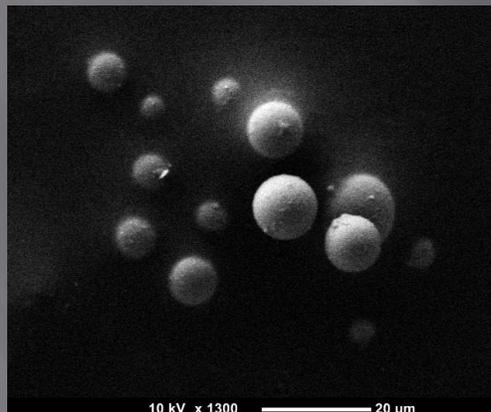


Ductile iron fracture

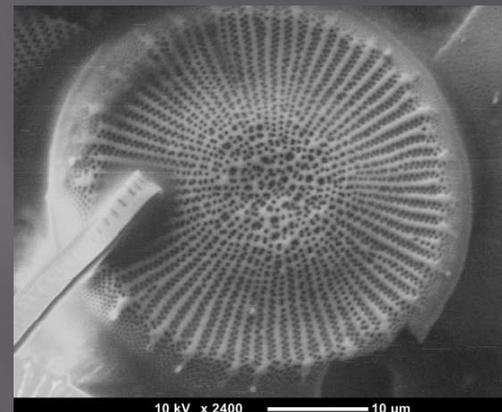
# JN-1 Non-Conductive Sample Images



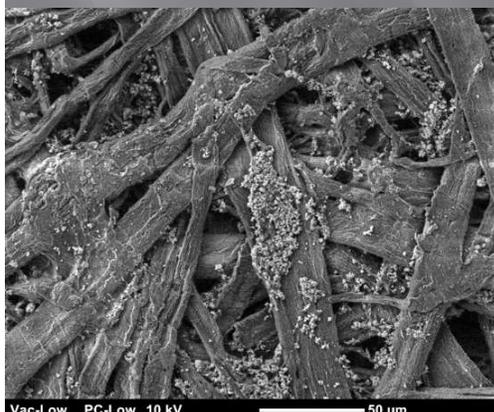
Fabric



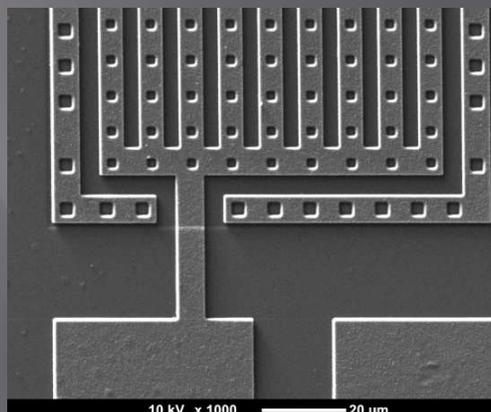
Glass spheres



Diatoms



Business card



Integrated circuit

Credits: SEM photographs taken on a JEOL Neoscope. Sample substitutions on this product will be considered. Jan. 2010